Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/073,106	YAMAMOTO ET AL.	AL.	
Examiner	Art Unit		
Paul D. Kim	3729		

	SEAR	CHED	
Class	Subclass	Date	Examiner
29	831 832 840 841 844 846 851 854	6/30/2005	PK
156	64 356	,	
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	DATE	EXMR
Text Search EAST/NPL (IEEE)	7/1/2005	PK
Consulted by John Vigushin (361)	2/1/2006	РК
Scott Geyer (438)	2/2/2006	PK
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Updated Text Search EAST	5/16/2006	РК
Updated Text Search EAST/PGPub	10/24/2006	PK